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Bruker Announces New High-Performance Scientific Instruments and Analytical Solutions at Pittcon 2013

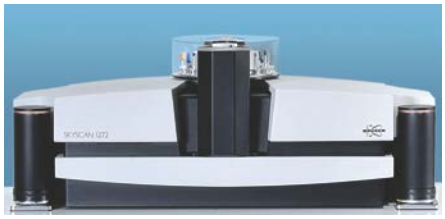
By Dr. Heiko Ress, Bruker AXS Inc., Madison, WI, USA

This week at Pittcon 2013, Bruker announced numerous new product introductions for research, industrial and applied markets, designed to deliver more confident analyses with increased sensitivity, specificity and productivity, as well as novel scientific capabilities that expand the boundaries of materials research. The new Bruker products introduced at Pittcon 2013 include:

ContourGT-K: The ContourGT-K 3D optical microscope offers imaging and metrology for the widest range of surfaces, and sets a new industry standard in design and cost for surface metrology performance. With exceptional roughness and 2D/3D measurement capabilities, high-resolution imaging and the industry's most advanced user interface, the system delivers uncompromised metrology in a simplified package with a compact footprint. The gage-capable ContourGT-K provides intuitive access to an extensive library of pre-programmed filters and analyses for LED, solar cell, thick films, semiconductor, ophthalmic, medical device, MEMS and tribology applications.

TITAN Detector Shield™: This unique accessory protects the detector window of the S1 TITAN handheld XRF analyzer from being punctured by sharp objects like scrap shavings and wires, without affecting its rapid and accurate elemental analysis of almost any material. The Detector Shield minimizes the likelihood of detector damage, thus avoiding the expense and inconvenience associated with the replacement of a broken detector window, without sacrificing any analytical performance, even for light elements like magnesium, aluminum and silicon.

SkyScan 1272: This innovative high-resolution X-ray µ-CT 3D microscope for materials and life science applications, can visualize up to 200 Megapixel (14,450 x 14,450 pixels) virtual slices through objects. More than 2,600 such slices can be reconstructed after a single data acquisition in up to three offset positions. Using advanced phase-contrast technology, the SkyScan 1272 can differentiate object details as small as 0.35 µm. An optional 16-position sample changer offers high throughput, even enabling the addition or replacement of samples without interrupting live scans. An optional GPU server and a cluster version of unique hybrid CPU/GPU software provide the fastest commercial µ-CT 3D reconstruction.



Bruker AXS Inc.
Madison, WI, USA
+1 800 234 9729
info@bruker-axs.com
www.bruker.com